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NATIONAL STANDARD OF THE

PEOPLE'S REPUBLIC OF CHINA

GB/T 5594.2-2026

Replacing GB/T 5594.2-1985

Test methods for electronic ceramic-Part 2:Poisson ratio

电子陶瓷测试方法 第2部分：泊松比

(English Translation)

Issued on: October 30, 2026 **Implemented on: May 1, 2027**

Issued by: State Administration for Market Regulation;
Standardization Administration of China

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1 Foreword

GB/T 5594.2-2026 was issued by State Administration for Market Regulation; Standardization Administration of China on 30 October 2026 and takes effect on 1 May 2027.

It replaces the earlier edition GB/T 5594.2-1985.

It is one of 14 parts of the GB/T 5594 series.

2 Scope Preview

GB/T 5594.2-2026 carries no ICS number and no Chinese Standard Classification code.

This catalogue holds 76,457 other GB/T standards.

Of the 47,415 GB/T standards that do carry an ICS number, 3,437 (7%) fall under ICS 77, in the field of metallurgy.

3 About this standard

Issued by: State Administration for Market Regulation; Standardization Administration of China

4 Related standards

Other parts of this standard:

GB/T 5594.1-1985 - Test methods for properties of structure ceramic used in electronic components. Test method for gas-tightness

GB/T 5594.3-1985 - Test methods for properties of structure ceramic used in electronic components--Test method for mean coefficient of linear expansion

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GB/T 5594.3-2015 - Test methods for properties of structure ceramic used in electronic components and device - Part 3: Test method for mean coefficient of linear expansion

GB/T 5594.4-1985 - Test methods for properties of structure ceramic used in electronic components--Test method for dielectric loss angle tangent value

GB/T 5594.4-2015 - Test methods for properties of structure ceramic used in electronic components and device - Part 4: Test method for permittivity and dielectric loss angle tangent value

GB/T 5594.5-1985 - Test methods for properties of structure ceramic used in electronic components. Test method for volume resistivity

GB/T 5594.5-2026 - Test methods for electronic ceramics-Part 5:Volume resistivity

GB/T 5594.6-1985 - Test methods for properties of structure ceramic used in electronic components--Test method for chemical durability

GB/T 5594.6-2015 - Test methods for properties of structure ceramics used in eletronic components and device-Part 6: Test method for chemical durability

GB/T 5594.7-1985 - Test methods for properties of structure ceramic used in electronic components--Test method for liquid permeability

GB/T 5594.7-2015 - Test methods for properties of structure ceramic used in electronic components and device-Part 7: Test method for liquid permeability

GB/T 5594.8-1985 - Test methods for properties of structure ceramic used in electronic components--Determination of microstructure

GB/T 5594.8-2015 - Test methods for properties of structure ceramic used in electronic components and device - Part 8: Test method for microstructure

Other editions:

GB/T 5594.2-1985 (earlier edition)

5 Classification and status

Prefix GB/T: recommended standard.

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